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	First Named Inventor	Yin, Zhiping	
FEB 2 8 2005	Group Art Unit	2829	
	Examiner Name	Wilson, Christian	
	Attorney Docket No: 3	03.864US1	

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Complete if Known **Application Number** 10/661379 September 12, 2003 **Filing Date** Yin, Zhiping **First Named Inventor Group Art Unit** 2661 **Examiner Name** Unknown

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OIPE	First Named Inventor	Yin, Zhiping
	Group Art Unit	2661
MAY 2 8 2004 E	Examiner Name	Unknown
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Filling Date September 12, 2003

First Named Inventor Yin, Zhiping

Group Art Unit 2661

Examiner Name Unknown

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